

FDZ375P P-Channel 1.5 V Specified PowerTrench<sup>®</sup> Thin WL-CSP MOSFET -20 V, -3.7 A, 78 m $\Omega$ 

## Features

- Max  $r_{DS(on)}$  = 78 m $\Omega$  at  $V_{GS}$  = -4.5 V,  $I_D$  = -2.0 A
- Max  $r_{DS(on)}$  = 92 m $\Omega$  at V<sub>GS</sub> = -2.5 V, I<sub>D</sub> = -1.5 A
- Max  $r_{DS(on)}$  = 112 m $\Omega$  at  $V_{GS}$  = -1.8 V,  $I_D$  = -1.0 A
- Max  $r_{DS(on)}$  = 150 m $\Omega$  at V<sub>GS</sub> = -1.5 V, I<sub>D</sub> = -1.0 A
- Occupies only 1.0 mm<sup>2</sup> of PCB area. Less than 30% of the area of 2 x 2 BGA
- Ultra-thin package: less than 0.4 mm height when mounted to PCB
- RoHS Compliant

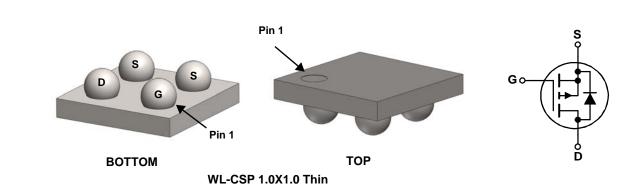


# **General Description**

Designed on Fairchild's advanced 1.5 V PowerTrench<sup>®</sup> process with state of the art "fine pitch" Thin WLCSP packaging process, the FDZ375P minimizes both PCB space and  $r_{DS(on)}$ . This advanced WLCSP MOSFET embodies a breakthrough in packaging technology which enables the device to combine excellent thermal transfer characteristics, ultra-low profile packaging, low gate charge, and low  $r_{DS(on)}$ .

# Applications

- Battery management
- Load switch
- Battery protection



# **MOSFET Maximum Ratings** T<sub>A</sub> = 25 °C unless otherwise noted

Symbol	Parameter			Ratings	Units	
V <sub>DS</sub>	Drain to Source Voltage			-20	V	
V <sub>GS</sub>	Gate to Source Voltage			±8	V	
1	-Continuous	T <sub>A</sub> = 25°C	(Note 1a)	-3.7		
D	-Pulsed			-12	— A	
P <sub>D</sub>	Power Dissipation	T <sub>A</sub> = 25°C	(Note 1a)	1.7		
	Power Dissipation	T <sub>A</sub> = 25°C	(Note 1b)	0.5		
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range			-55 to +150	°C	

## **Thermal Characteristics**

$R_{ ext{ heta}JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	75	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1b)	260	C/VV

## Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
Ν	FDZ375P	WL-CSP 1.0X1.0 Thin	7 "	8 mm	5000 units

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Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	I <sub>D</sub> = -250 μA, V <sub>GS</sub> = 0 V	-20			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = -250 \ \mu$ A, referenced to 25 °C		-12		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -16 V, V <sub>GS</sub> = 0 V			-1	μA
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 8 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA
On Chara	cteristics					
V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = -250 μA	-0.3	-0.5	-1.2	V
$\frac{\Delta V_{GS(th)}}{\Delta T_{J}}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = -250 \ \mu\text{A}$ , referenced to 25 °C		2		mV/°C
0	Static Drain to Source On Resistance	$V_{GS}$ = -4.5 V, I <sub>D</sub> = -2.0 A		65	78	mΩ
r <sub>DS(on)</sub> Static Drain to Source On Resistance		$V_{GS} = -2.5 \text{ V}, \text{ I}_{D} = -1.5 \text{ A}$		77	92	
		V <sub>GS</sub> = -1.8 V, I <sub>D</sub> = -1.0 A		92	112	
		V <sub>GS</sub> = -1.5 V, I <sub>D</sub> = -1.0 A		112	150	
		V <sub>GS</sub> = -4.5 V, I <sub>D</sub> = -2.0 A, T <sub>.1</sub> =125°C		98	143	
9 <sub>FS</sub>	Forward Transconductance	V <sub>DD</sub> = -5 V, I <sub>D</sub> = -3.3 A		11		S
	Characteristics					
C <sub>iss</sub>	Input Capacitance			650	865	pF
C <sub>oss</sub>	Output Capacitance	── V <sub>DS</sub> = -10 V, V <sub>GS</sub> = 0 V, f = 1 MHz		110	145	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			95	150	pF
Switching	Characteristics					
t <sub>d(on)</sub>	Turn-On Delay Time			5.3	11	ns
t <sub>r</sub>	Rise Time	$V_{DD}$ = -10 V, I <sub>D</sub> = -3.3 A, V <sub>GS</sub> = -4.5 V, R <sub>GEN</sub> = 6 Ω		8.2	15	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			138	221	ns
t <sub>f</sub>	Fall Time			84	124	ns
Q <sub>q</sub>	Total Gate Charge	V <sub>GS</sub> = -4.5 V, V <sub>DD</sub> = -10 V, I <sub>D</sub> = -3.3 A		11	15	nC
Q <sub>gs</sub>	Gate to Source Charge			0.8		nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge	- ID3.3 A		3		nC
Drain-Sou	urce Diode Characteristics					
I <sub>S</sub>	Maximum Continuous Drain-Source Diode	Forward Current			-1.1	Α
V <sub>SD</sub>	Source to Drain Diode Forward Voltage	$V_{GS} = 0 V, I_{S} = -1.3 A$ (Note 2)		-0.7	-1.2	V
t <sub>rr</sub>	Reverse Recovery Time			68	109	ns
Q <sub>rr</sub>	Reverse Recovery Charge	— I <sub>F</sub> = -3.3 A, di/dt = 100 A/μs		43	69	nC

Notes:

 $R_{0JA}$  is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material.  $R_{0JC}$  is guaranteed by design while  $R_{0CA}$  is determined by the user's board design.

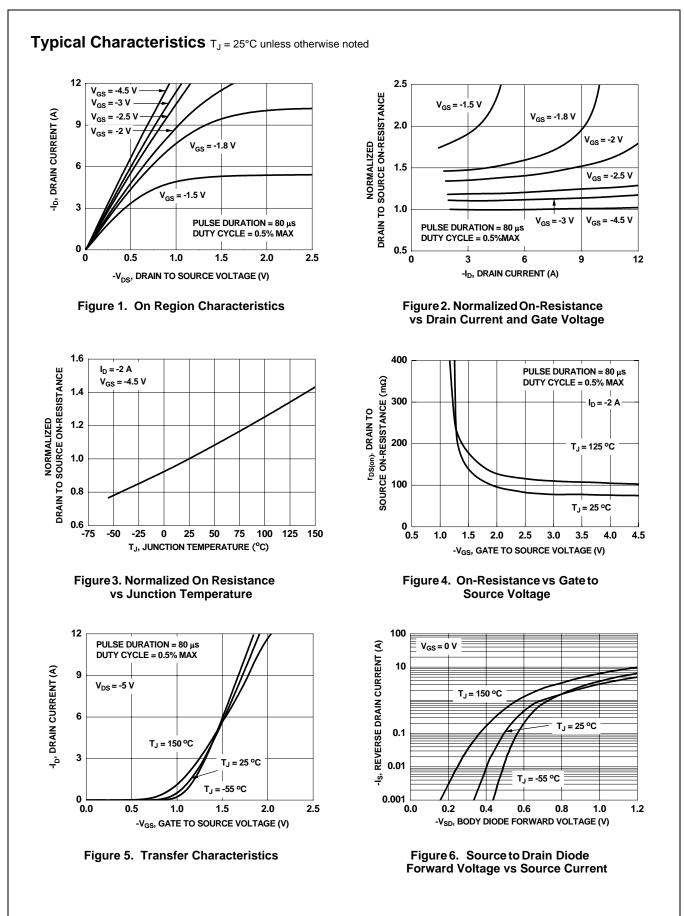


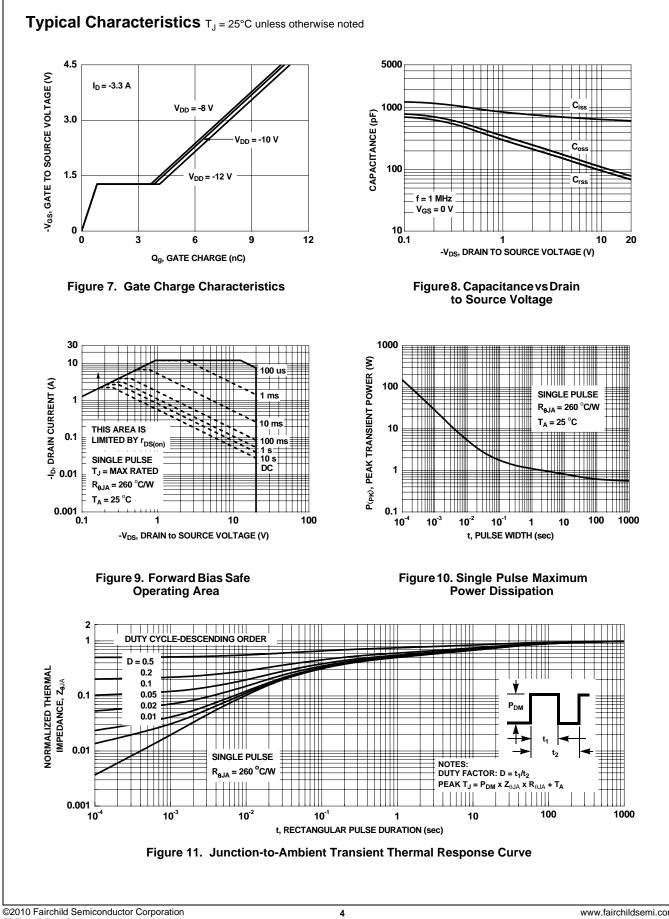
a. 75 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.

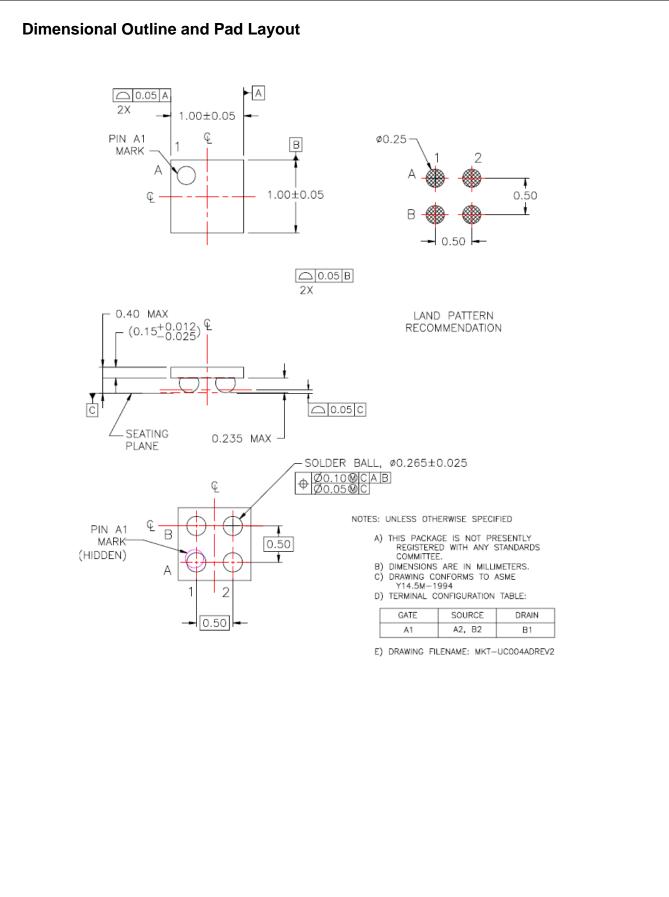
b. 260 °C/W when mounted on a minimum pad of 2 oz copper.

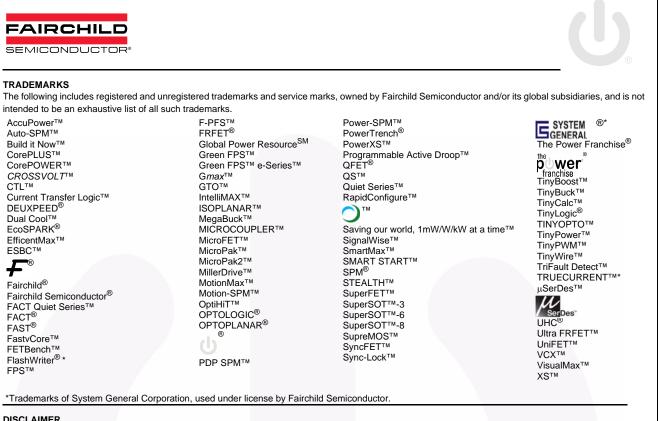
2. Pulse Test: Pulse Width < 300 $\mu$ s, Duty cycle < 2.0%.











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